

**Search Notes****Application/Control No.**

10/698,222

**Examiner**

Toan M. Le

**Applicant(s)/Patent under Reexamination**

SHI ET AL.

**Art Unit**

2863

**SEARCHED**

Class	Subclass	Date	Examiner
702	57	3/24/2005	TL
324	671	3/24/2005	TL
324	455	3/24/2005	TL
438	17	3/24/2005	TL
438	16	3/24/2005	TL
324	765	3/24/2005	TL
Above	Updated	9/26/2005	TL
Above	Updated	4/12/2006	TL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
702	57	4/12/2006	TL
438	17	4/12/2006	TL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Contactless Insulating Dielectric Film Characterization	3/23/2005	TL
Substrate, Dielectric Film, Voltage, Kelvin Probe	3/23/2005	TL
Substrate, Film, Thickness, Nitrogen, Charge, Non-Contact	3/18/2005	TL
Insulating Film, Surface Voltage, Charge, Deposition, Average	9/26/2005	TL
Insulating Film, Surface Voltage, Charge, Deposition	4/12/2006	TL
702/57; 324/671,455,765; 438/17,16 (Insulating Film, Thickness)	4/12/2006	TL
ScienceDirect, IEEE Xplore	4/12/2006	TL
East- See Search History Printout	4/12/2006	TL